## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): Rankin, et al. Examiner: Doty, Heather Anne

Serial No.: 10/710,602 Group Art Unit: 2813

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Title: METHOD TO SELECTIVELY CORRECT CRITICAL DIMENSION ERRORS IN

THE SEMICONDUCTOR INDUSTRY

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

## REQUEST FOR RECONSIDERATION

Sir:

This Request for Reconsideration is in response to the Office Action mailed March 30, 2006.